

INFORMATION DISCLOSURE  
CITATION

PTO-1449

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015780-034APPLICATION NO.  
09/632,631APPLICANT  
Naulleau et al.FILING DATE  
August 4, 2000GROUP  
2877

## U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE

## FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation Yes No
<i>all</i>	WO92/2099	11-26-92	PCT			

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

<i>rd</i>	Kim S-W, et al., "Lateral-shearing Interferometer Using Square Prisms for Optical Testing of Aspheric Lenses", Measurement Science and Technology, IOP Publishing, Bristol, GB, Vol. 9, July 1998, pages 1129-1136.

EXAMINER

DATE CONSIDERED

*5/24/03*

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No

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